

## 1. Product Information

**Supplier :** JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO.,LTD.

|                      |              |
|----------------------|--------------|
| <b>Part Number:</b>  | CJP021SN15MK |
| <b>Package Type:</b> | TO-220-3L-CB |
| <b>Report Date:</b>  | April-2026   |

## 2. Reference Standard

| Item                    | Standards   |
|-------------------------|-------------|
| 1.Human-Body Model(HBM) | JESD22-A114 |
| 2.Machine Model(MM)     | JESD22-A115 |

## 3. Classification Criteria

| HBM Classification level |                           |
|--------------------------|---------------------------|
| Level                    | Test Voltage              |
| CLASS 0                  | $\leq 250V$               |
| CLASS 1A                 | $> 250V$ to $\leq 500V$   |
| CLASS 1B                 | $> 500V$ to $\leq 1000V$  |
| CLASS 1C                 | $> 1000V$ to $\leq 2000V$ |
| CLASS 2                  | $> 2000V$ to $\leq 4000V$ |
| CLASS 3A                 | $> 4000V$ to $\leq 8000V$ |
| CLASS 3B                 | $> 8000V$                 |

| MM Classification level |                         |
|-------------------------|-------------------------|
| Level                   | Test Voltage            |
| CLASS A                 | $< 200V$                |
| CLASS B                 | $\geq 200V$ to $< 400V$ |
| CLASS C                 | $\geq 400V$             |

## 4. Test Result

| Test Item | Test Condition                                    | Samples | Class Level |
|-----------|---------------------------------------------------|---------|-------------|
| HBM       | Interval:1s 3Times /200V~8000V step:200V( $\pm$ ) | 5PCS    | CLASS 1B    |
| MM        | Interval:1s 3Times /200V~800V step:200V( $\pm$ )  | 5PCS    | CLASS B     |

## Notes:

The failure criterion for the ESD test is based on whether the Device Under Test (DUT) meets its product specification (datasheet). Specifically, after being subjected to the specified ESD pulse stress, the device must undergo electrical parameter testing and functional checks. The device shall be considered failed if any of the following conditions occur:

- 1) Electrical parameters deviate from the limits specified in the datasheet;
- 2) Logic functions or preset functions cannot be realized.

Remark: JSCJ Laboratory reserves the right of final interpretation of this report